

Notice of References Cited	Application/Control No. 10/524,227		Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner LINH T. NGUYEN		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,633,515	10-2003	Van Nieuwenhoven et al.	369/30.04
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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	J	US-			
	K	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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